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Insamling, logistik och behandling av skrotad elektrisk och elektronisk utrustning (WEEE) – Del 3-3: Sanering av utrustning som innehåller katodstrålerör eller platta bildskärmar

Collection, logistics & treatment requirements for WEEE – Part 3-3: Specification for de-pollution – WEEE containing CRTs and flat panel displays (CENELEC Technical Specification 50625-3-3:2017)

Nationellt förord

En teknisk specifikation, TS, utarbetad inom CENELEC är avsedd att ge beskrivningar som kan stödja den inre marknads utveckling, ge vägledning beträffande specifikationer eller provningsmetoder eller ge specifikationer för teknikområden under snabb utveckling. Ett förslag till europeisk standard, EN, som det inte varit möjligt att nå tillräcklig enighet kring, kan också fastställas som TS, för att användas på försök (som förstandard) och för att efter eventuella justeringar eller bearbetningar senare fastställas som EN. En teknisk specifikation har en giltighetstid som är begränsad till tre år, med möjlighet till förlängning med tre eller högst sex år.

SEK TS 50625-3-3 ska användas tillsammans med SEK TS 50625-3-1.

Standarder underlättar utvecklingen och höjer elsäkerheten

Det finns många fördelar med att ha gemensamma tekniska regler för bl a mätning, säkerhet och provning och för utförande, skötsel och dokumentation av elprodukter och elanläggningar.

Genom att utforma sådana standarder blir säkerhetsfordringar tydliga och utvecklingskostnaderna rimliga samtidigt som marknadens acceptans för produkten eller tjänsten ökar.

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SEK samordnar svenska intressenters medverkan i SEKs tekniska kommittéer och stödjer svenska experters medverkan i internationella och europeiska projekt.

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Utformningen av standarder sker i allt väsentligt i internationellt och europeiskt samarbete. SEK är svensk nationalkommitté av International Electrotechnical Commission (IEC) och Comité Européen de Normalisation Electrotechnique (CENELEC).

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English Version

Collection, logistics & treatment requirements for WEEE - Part 3-3: Specification for de-pollution - WEEE containing CRTs and flat panel displays

Exigences de collecte, logistique et traitement pour les déchets d'équipements électriques et électroniques (DEEE)
- Partie 3-3: Spécifications relatives à la dépollution - DEEE contenant des tubes cathodiques et des écrans plats

Sammlung, Logistik und Behandlung von Elektro- und Elektronik-Altgeräten (WEEE) - Teil 3-3: Spezifikation der Schadstoffentfrachtung - WEEE mit CRT und Flachbildschirmgeräten

This Technical Specification was approved by CENELEC on 2017-06-19.

CENELEC members are required to announce the existence of this TS in the same way as for an EN and to make the TS available promptly at national level in an appropriate form. It is permissible to keep conflicting national standards in force.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Croatia, Cyprus, the Czech Republic, Denmark, Estonia, Finland, Former Yugoslav Republic of Macedonia, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Serbia, Slovakia, Slovenia, Spain, Sweden, Switzerland, Turkey and the United Kingdom.



European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

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European foreword

This document (CLC/TS 50625-3-3:2017) has been prepared by CLC/TC 111X “Environmental aspects for electrical and electronic products and systems”.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC shall not be held responsible for identifying any or all such patent rights.

This document has been prepared under a mandate given to CENELEC by the European Commission and the European Free Trade Association, and supports essential requirements of EU Directive(s).

EN 50625 is currently composed of the following parts:

- EN 50625-1, *Collection, logistics and Treatment requirements for WEEE — Part 1: General treatment requirements*;
- EN 50625-2-1, *Collection, logistics and Treatment requirements for WEEE — Part 2-1: Treatment requirements for lamps*;
- CLC/TS 50625-3-1, *Collection, logistics and treatment requirements for WEEE — Part 3-1: Specification for de-pollution — General*;
- CLC/TS 50625-3-3, *Collection, logistics and treatment requirements for WEEE — Part 3-3: WEEE containing CRTs and flat panel displays* [the present document].

This document has been prepared under mandate M/518 given to CENELEC by the European Commission and the European Free Trade Association.

This CLC/TS 50625-3-3 is to be used in conjunction with CLC/TS 50625-3-1.

This CLC/TS 50625-3-3 supplements or modifies the corresponding clauses in CLC/TS 50625-3-1, so as to convert that publication into the TS: Treatment specification for de-pollution - WEEE containing CRTs and flat panel displays.

When a particular subclause of CLC/TS 50625-3-1 is not mentioned in this CLC/TS 50625-3-3, that subclause applies as far as it is reasonable. When this standard states “addition”, “modification” or “replacement”, the relevant text in CLC/TS 50625-3-1 is to be adapted accordingly.

NOTE The following numbering system is used:

— subclauses, tables and figures that are numbered starting from 101 are additional to those in CLC/TS 50625-3-1;

— unless notes are in a new subclause or involve notes in Part 1, they are numbered starting from 101, including those in a replaced clause or subclause;

— additional annexes are lettered AA, BB, etc.

Introduction

In order to support EN 50625-2-2 *Treatment requirements for WEEE containing CRTs and flat panel displays* and thereby fulfil the requirement of the European Commission's Mandate M/518, it is necessary to include normative requirements (such as target and limit values for the analysis) into a document, which is able to be revised in the future, to take into account both practical experiences and changes in treatment technologies.

1 Scope

Clause 1 of CLC/TS 50625-3-1:2015 is replaced with the following:

This European Technical Specification is intended to be used in conjunction with *Collection, logistics and treatment requirements for WEEE — Part 1: General treatment requirements*, EN 50625-1, *Collection, logistics and Treatment requirements for WEEE — Part 2-2: Treatment requirements for WEEE containing CRTs and flat panel displays*, EN 50625-2-2 and *Collection, logistics and treatment requirements for WEEE — Part 3-1: Specification for de-pollution — General*, CLC/TS 50625-3-1.

2 Normative references

Clause 2 of CLC/TS 50625-3-1:2015 is replaced with the following:

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 11885, *Water quality — Determination of selected elements by inductively coupled plasma optical emission spectrometry (ICP-OES)*

EN ISO 12846, *Water quality - Determination of mercury - Method using atomic absorption spectrometry (AAS) with and without enrichment (ISO 12846)*

EN 13657, *Characterization of waste - Digestion for subsequent determination of aqua regia soluble portion of elements*

EN 13656, *Characterization of waste - Microwave assisted digestion with hydrofluoric (HF), nitric (HNO₃) and hydrochloric (HCl) acid mixture for subsequent determination of elements*

EN 14899, *Characterization of waste - Sampling of waste materials - Framework for the preparation and application of a Sampling Plan*

EN 15002, *Characterization of waste - Preparation of test portions from the laboratory sample*

EN 15309, *Characterization of waste and soil - Determination of elemental composition by X-ray fluorescence*

ISO 16772, *Soil quality — Determination of mercury in aqua regia soil extracts with cold-vapour atomic spectrometry or cold-vapour atomic fluorescence spectrometry*

EN ISO 17294-2, *Water quality - Application of inductively coupled plasma mass spectrometry (ICP-MS) - Part 2: Determination of selected elements including uranium isotopes (ISO 17294-2)*

ISO/IEC 17025:2005, *General requirements for the competence of testing and calibration laboratories*

ISO 17852, *Water quality — Determination of mercury — Method using atomic fluorescence spectrometry*

EN 50625-1, *Collection, logistics & Treatment requirements for WEEE - Part 1: General treatment requirements*

CLC/TS 50625-3-1, *Collection, logistics & treatment requirements for WEEE - Part 3-1: Specification for de-pollution - General*

EN 50625-2-2, *Collection, logistics & Treatment requirements for WEEE - Part 2-2: Treatment requirements for WEEE containing CRTs and flat panel displays*